

SILICON PHOTONICS SOLUTIONS WITH CELADON

Silicon Photonics Solutions

Flexible solutions for a wide range of demanding test requirements

Celadon is the market leader in specialty and high-performance probe cards, and we are known for wafer level characterization, reliability testing, and parametric testing across a wide variety of test conditions.

Because we machine all our probe card components internally, we can support a wide variety of formats needed to support silicon photonics device development and production-level testing.

Celadon has worked closely with customers and supplier partners to enable electrical testing in parallel with optical testing for a wide variety silicon photonics devices, pad layouts and test conditions.

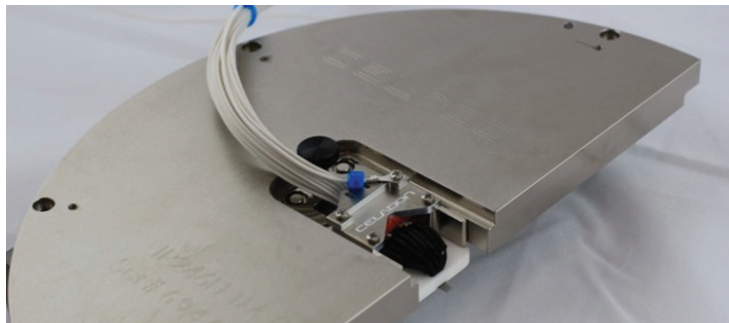


Figure 1 - Celadon MiniTile probe card with half circle mounting system design for characterization and WLR with a Keysight tester.

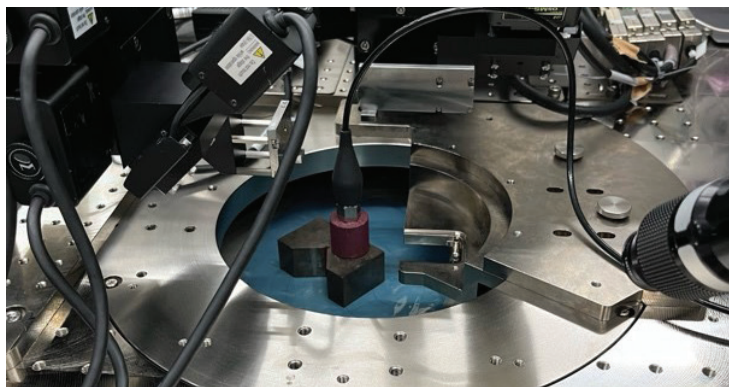


Figure 2 - Keysight set-up working with the Celadon MiniTile probe card enables optical testing on one side of the platen and electrical testing in parallel on the other side of the platen.

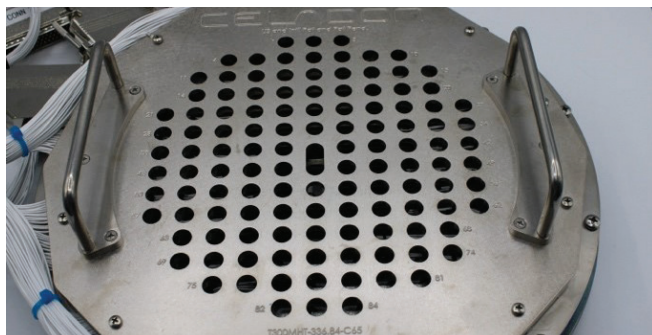


Figure 3 - Celadon's T300 with enlarged windows to enable long-term wafer level reliability testing of micro-LEDs on an MPI TS2000 prober.

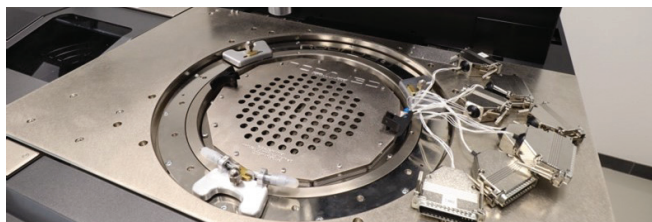


Figure 4 - Celadon's T300 mounted on the MPI TS2000 prober. The enlarged windows and prober set-up enable full-wafer electrical testing of microLEDs while monitoring optical characteristics in parallel.



Figure 5 - Celadon's T90 probe card with a custom design featuring a large window to provide access to fiber array bundles for multisite optical testing in parallel with multisite WLR.